Exhibitor Technology Spotlight Workshops
Room Hall A - Session EW-WeB

Exhibitor Technology Spotlight Session IV
Moderator: Christopher Moffitt, Kratos Analytical Inc

10:20am **EW-WeB-2 HAXPES-Lab: A Laboratory Based System for HAXPES Measurements*, Susanna Eriksson,*** Scienta Omicron

Scienta Omicron's HAXPES-Lab brings hard X-ray photoelectron spectroscopy (HAXPES) capability directly to the end user's laboratory. This novel system enables the investigation of buried interfaces, in-operando devices and real world samples, all without the need for a synchrotron end station. By combining a state-of-the-art, monochromized 9.25keV Ga X-ray source with the proven Scienta Omicron wide acceptance angle hemispherical analyzer, the HAXPES-Lab sets the standard for laboratory based high energy photoelectron spectroscopy.

10:40am **EW-WeB-3 Coatings Characterization Solution from Fischer Technology - XRF, Nanoindentation and Progressive Load Scratch*, Rahul Nair,*** Fischer Scientific

This talk discusses the key features that aid in increased productivity and usability of the Fischer's non-destructive coating thickness (XRF) and mechanical (nanoindentation and scratch) testers. Fischer is a pioneer in the field of nanoindentation (since 1985) and XRF (since 19XX). The standard measurement and computation of coating thickness and mechanical properties are performed in accordance to ISO and ASTM standards with minimal influence by the operator. Fischer's primary focus has been on reduced measuring time and higher throughput while producing accurate and precise measurements. Some of the key features in our nanoindentation and scratch testers that aid this are single-step tests, programmable test cycles, significantly reduced time to detect surface, improved autofocus, graphical presentations and automated report generation. Additionally, because of the high resolutions for load and distance the Fischer instruments can be used for a broad range of applications and materials. It is even possible to determine the plastic and elastic material properties of even very hard and thin coatings.

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